## Application/Control No. Applicant(s)/Patent Under Reexamination 10/650,365 WEI ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1647 Jegatheesan Seharaseyon, Ph.D **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С US-D Ε US-US-F US-G US-Н ı US-US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Name Classification Country Country Code-Number-Kind Code MM-YYYY EP422697A1 04-1991 Alton et al. Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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